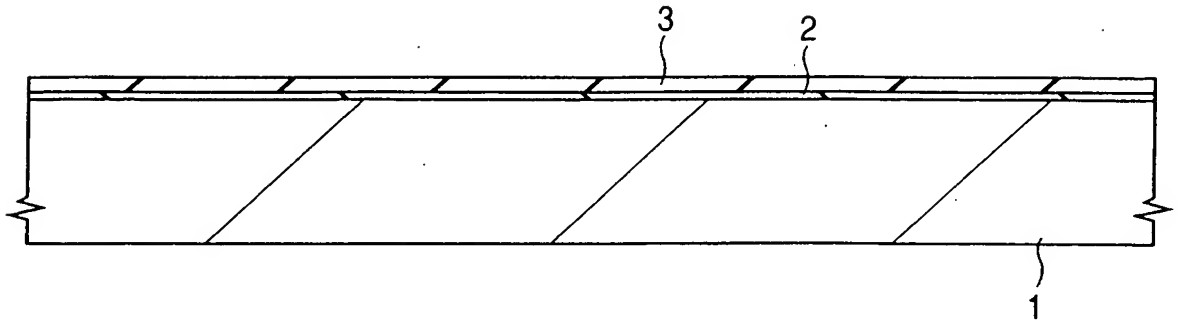
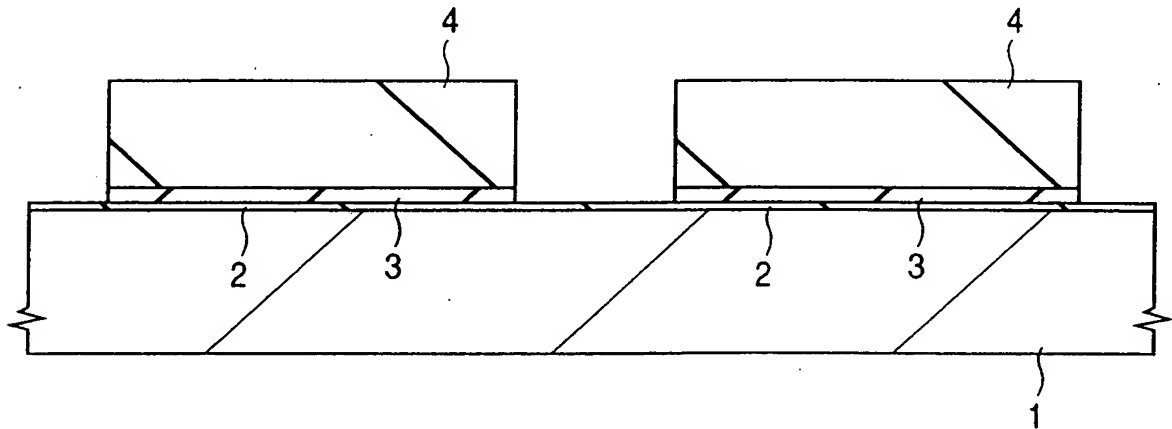


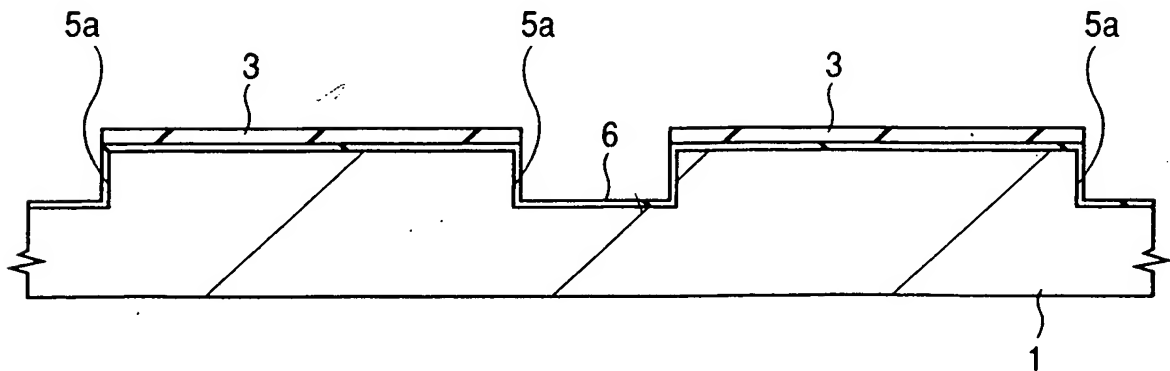
**FIG. 1**

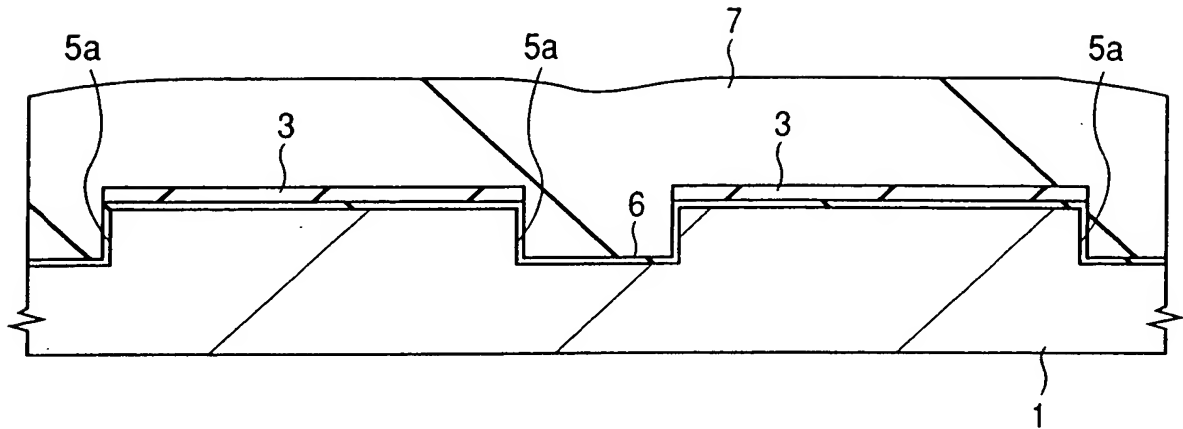
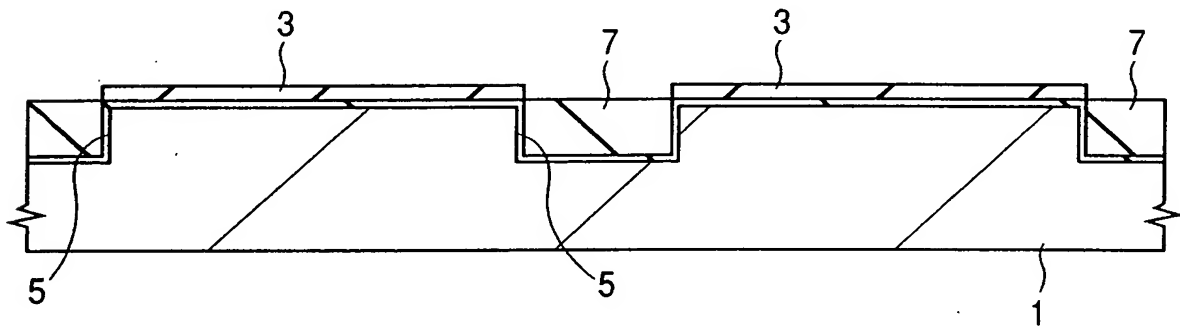
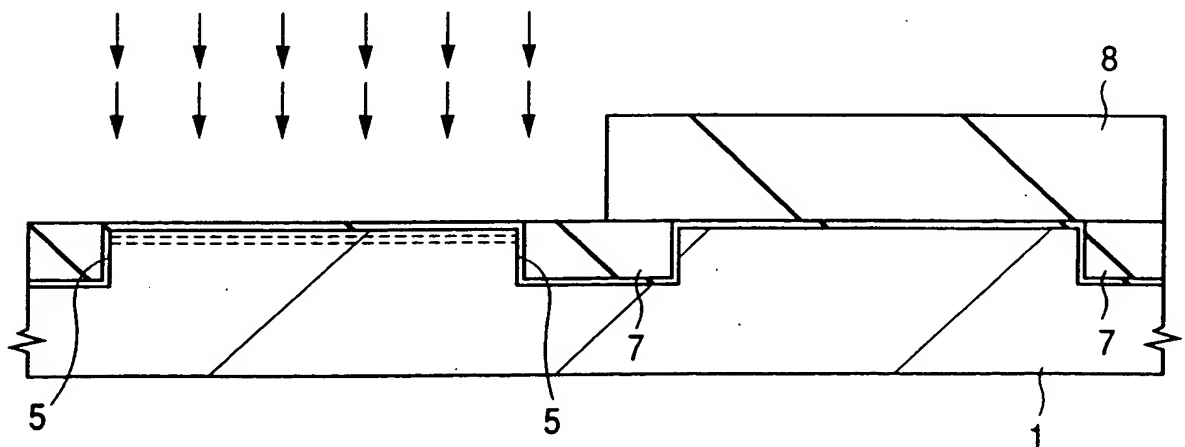


**FIG. 2**

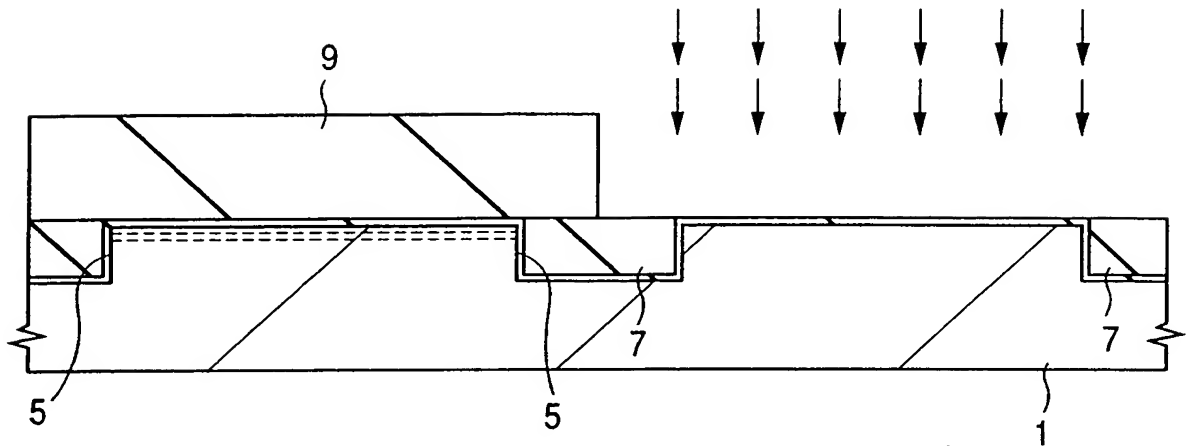


**FIG. 3**

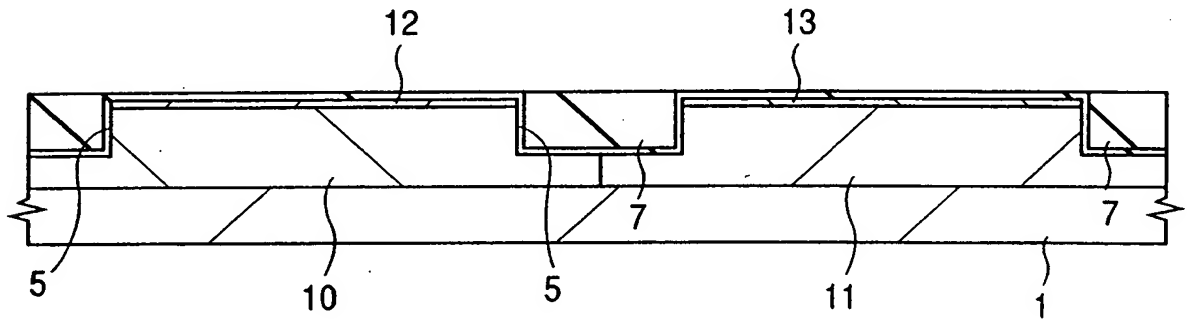


**FIG. 4****FIG. 5****FIG. 6**

**FIG. 7**



**FIG. 8**



**FIG. 10**

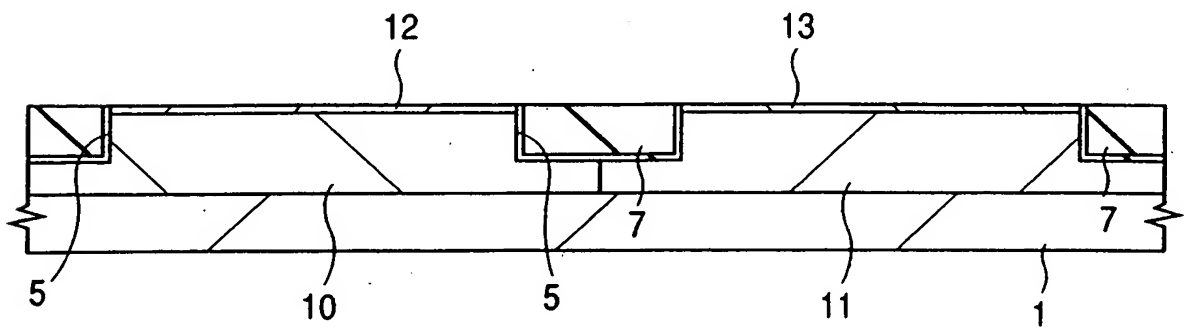
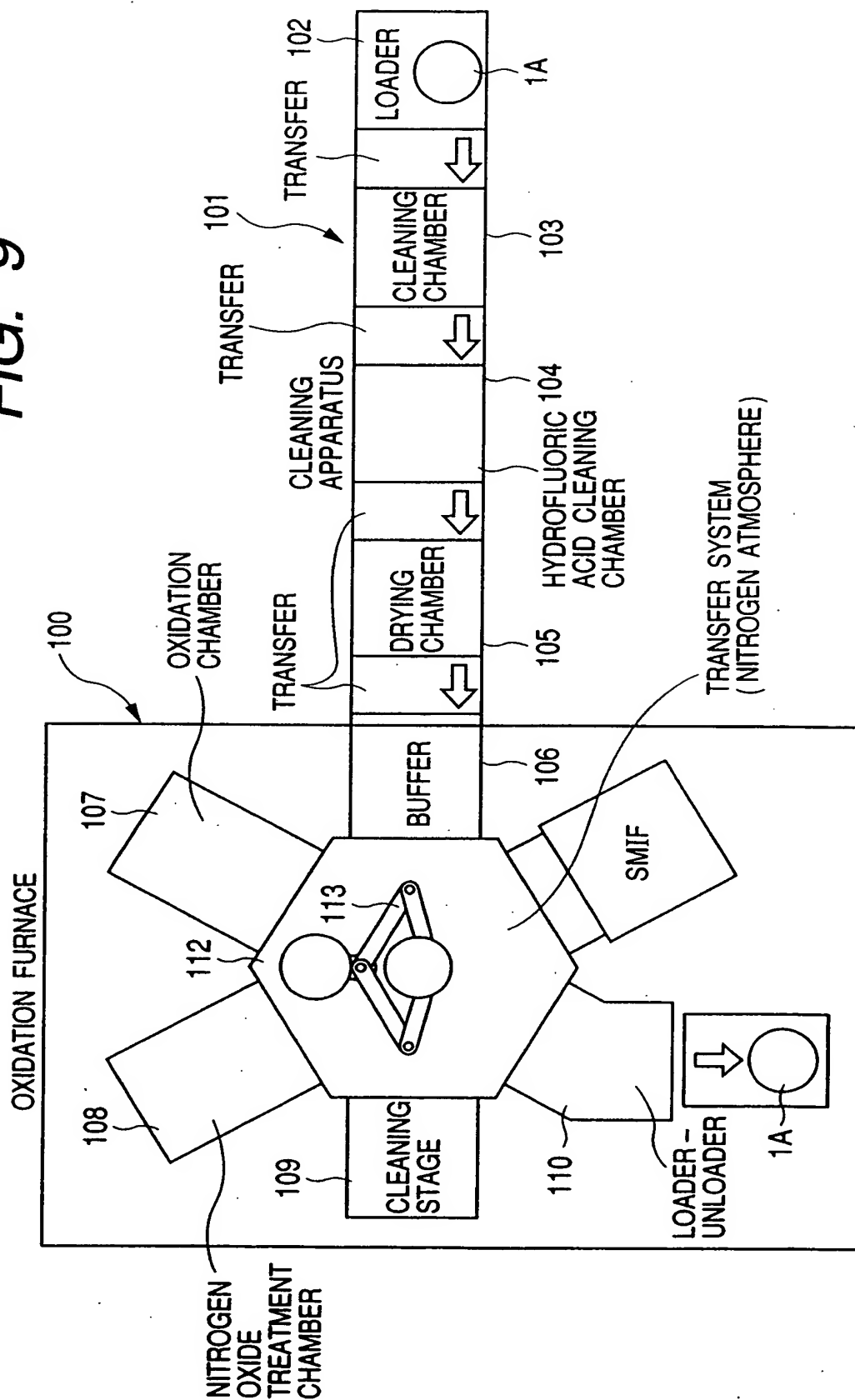
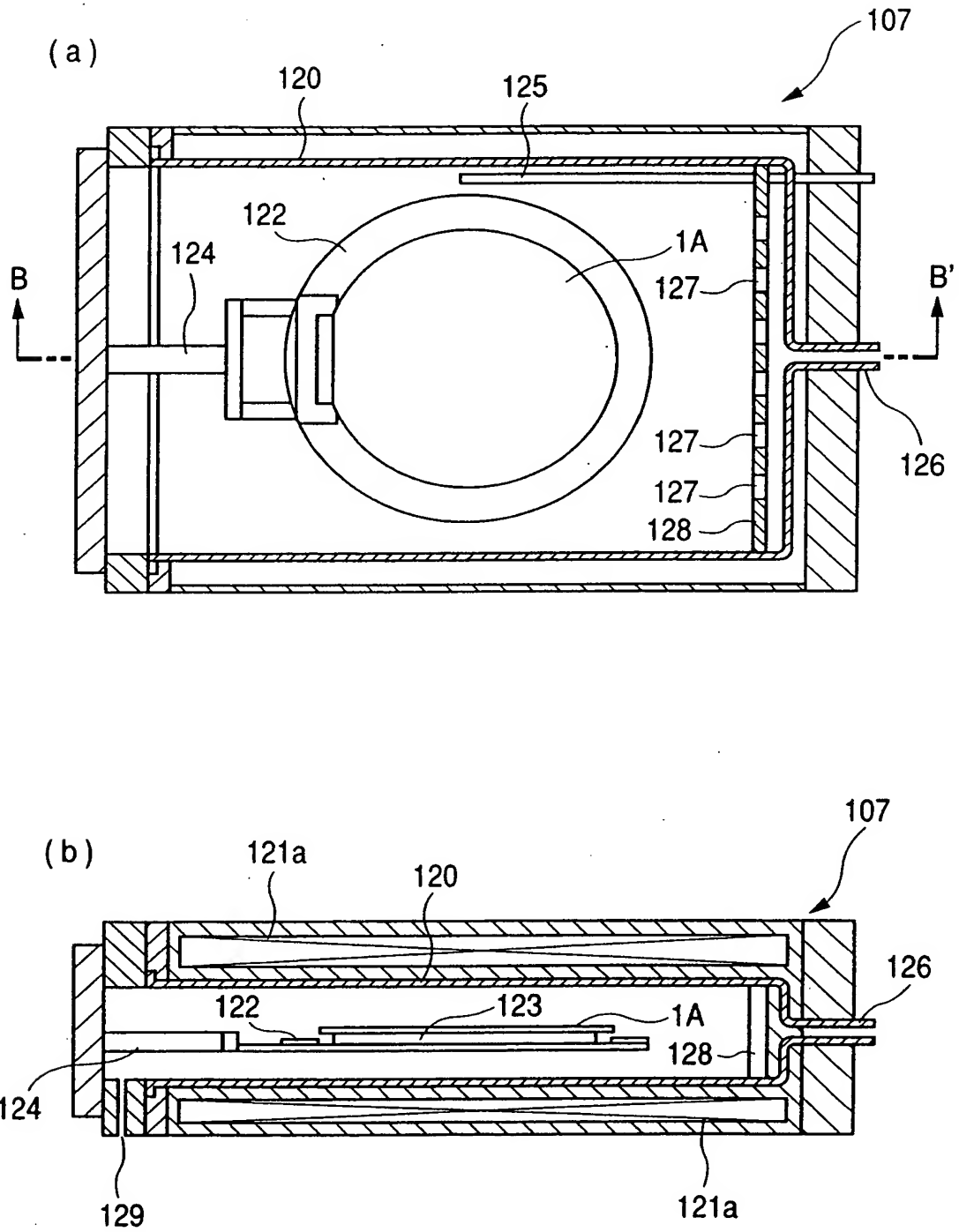


FIG. 9



**FIG. 11**

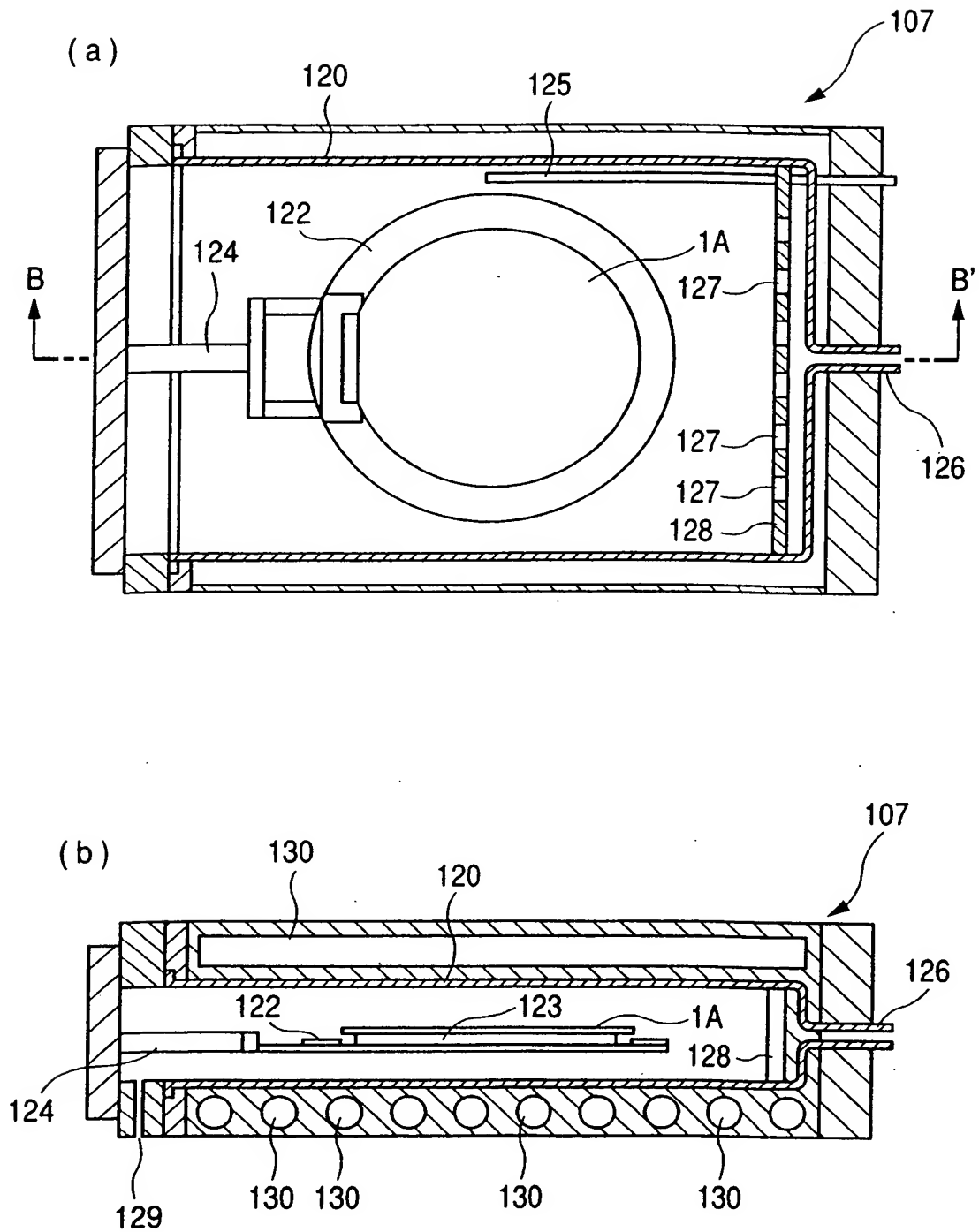
**FIG. 12**

FIG. 13

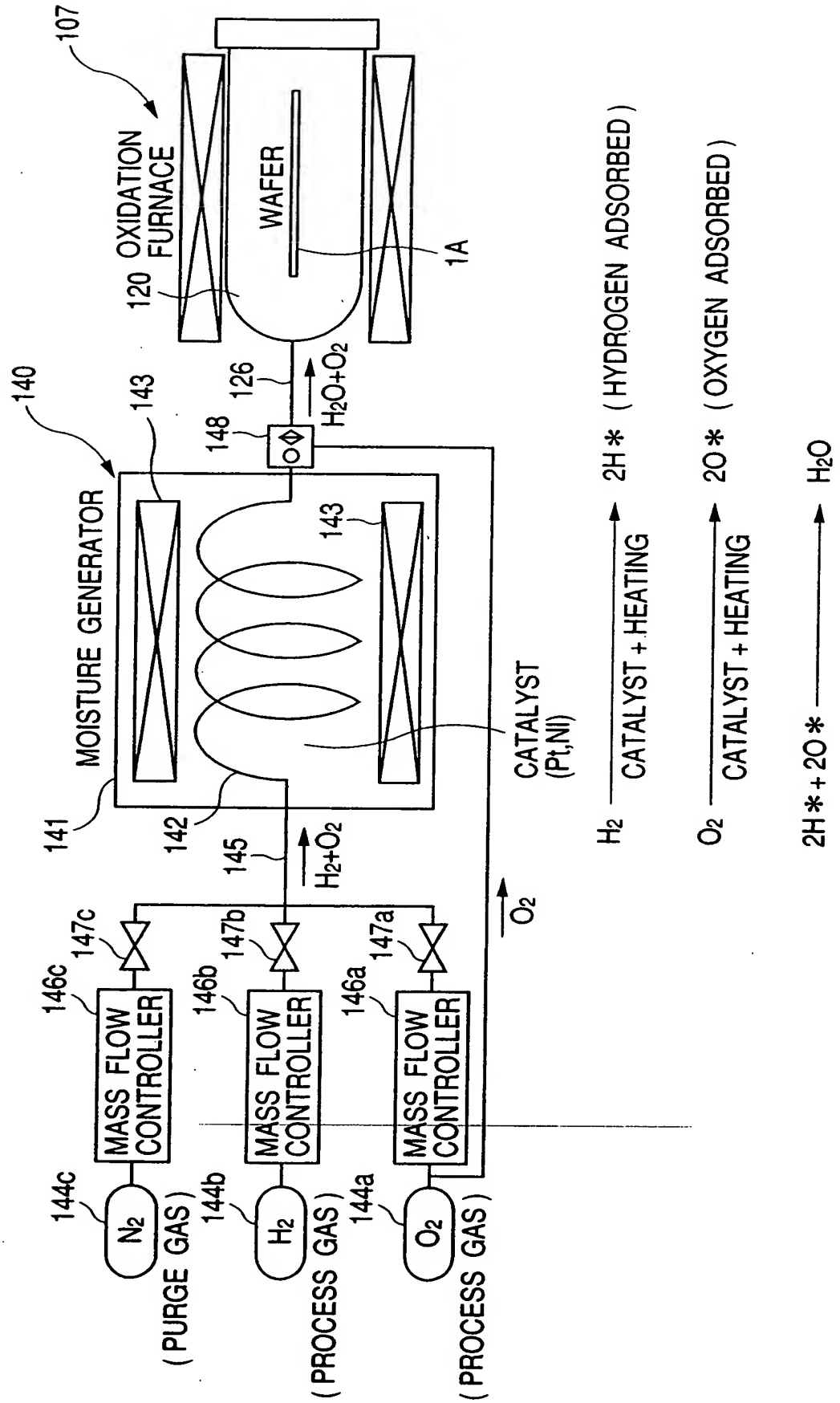


FIG. 14

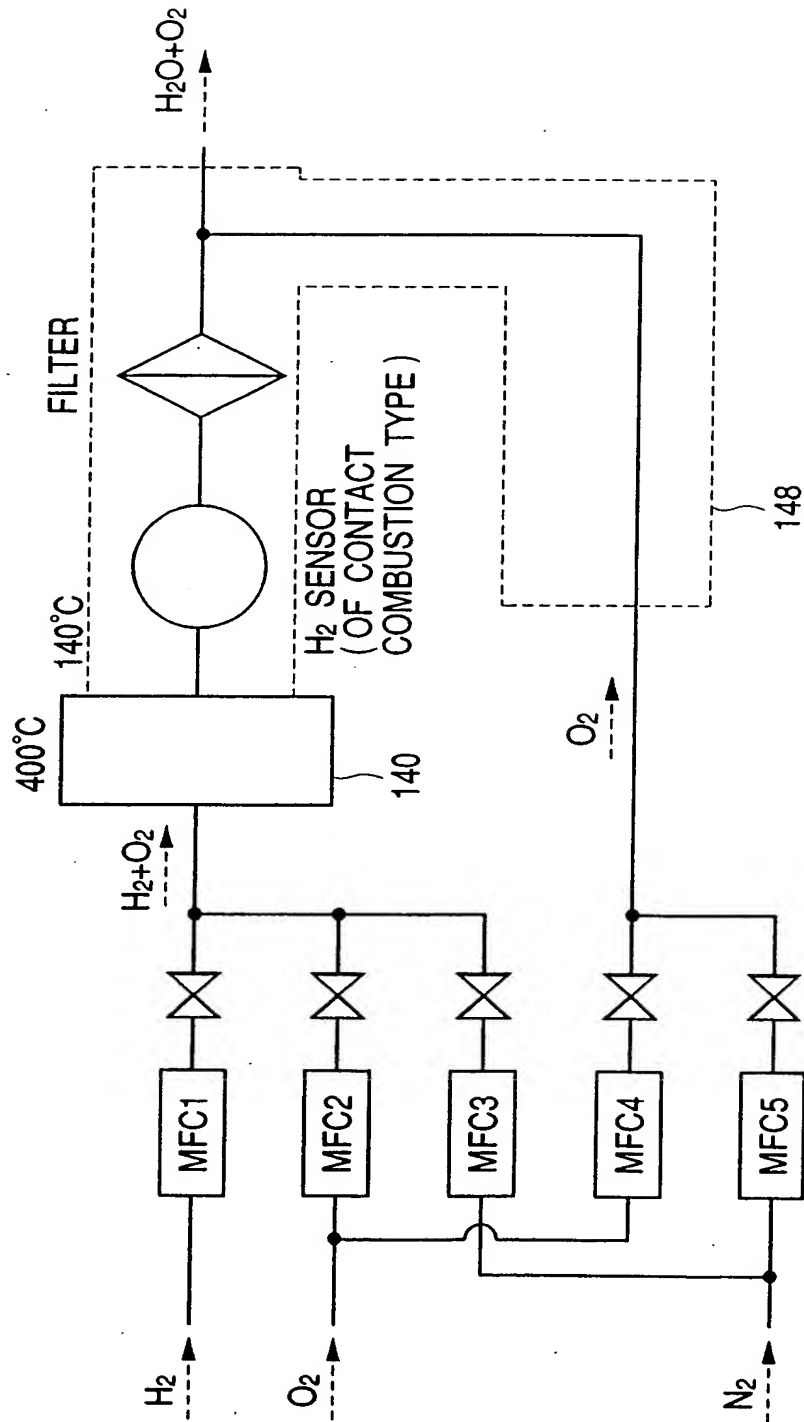
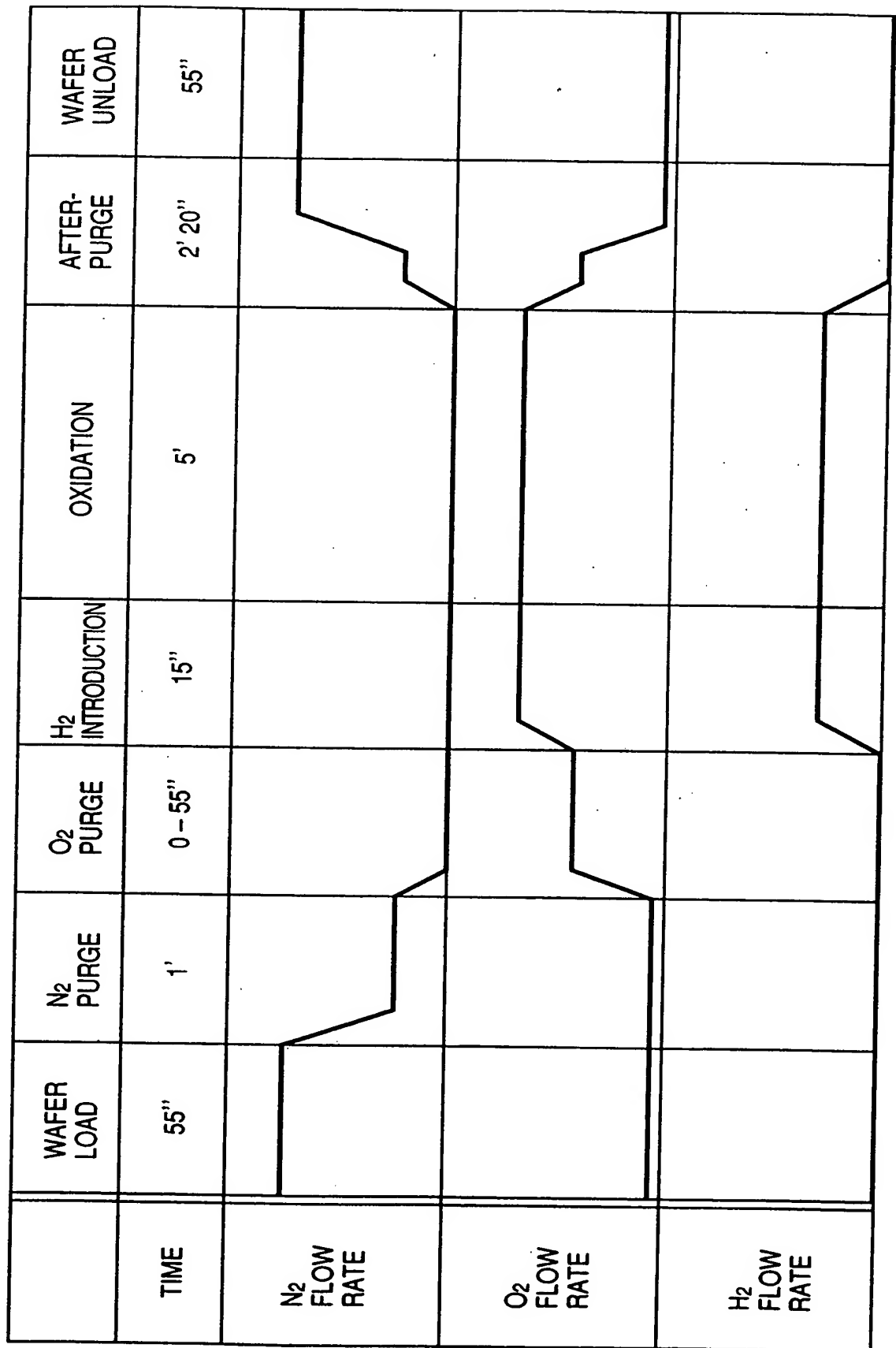


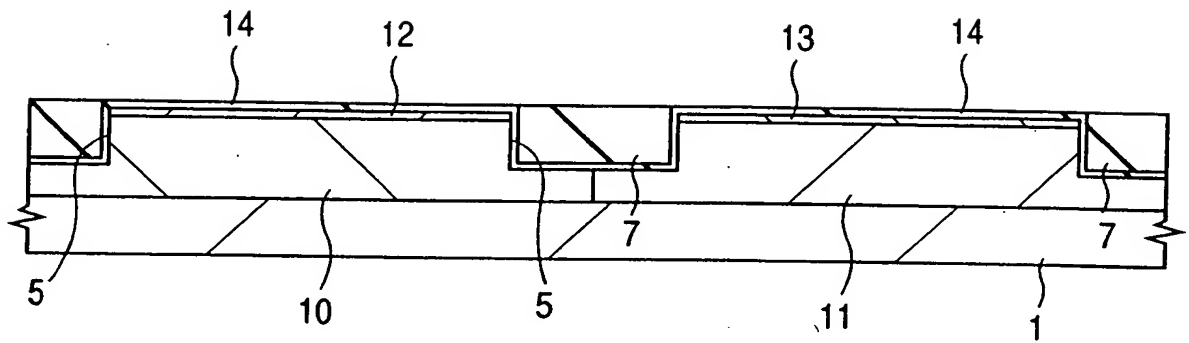


FIG. 15

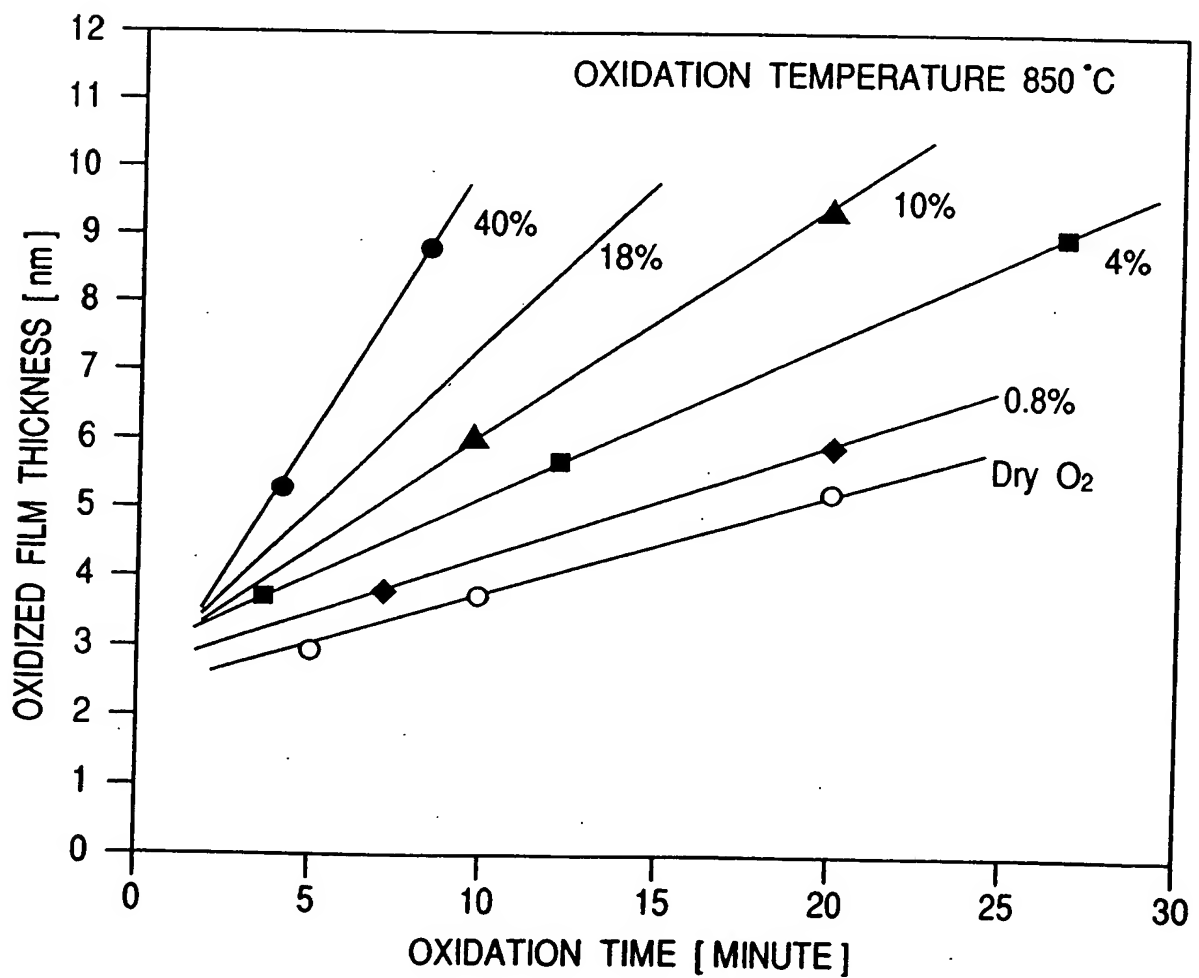


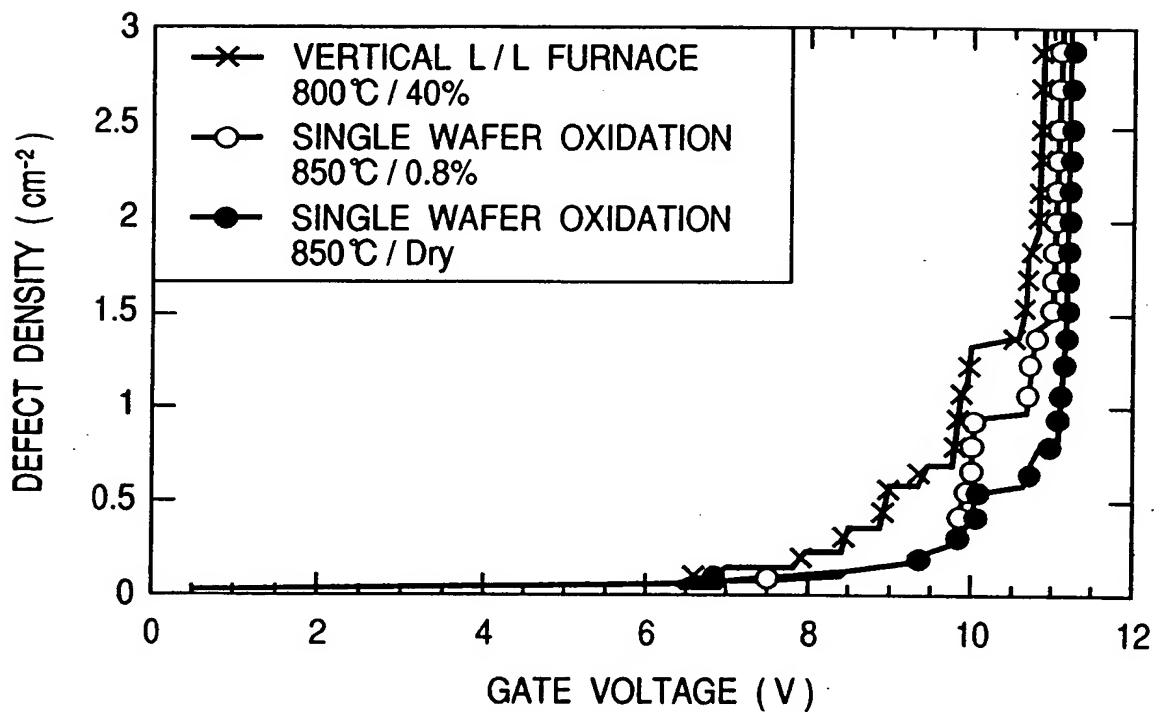
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**FIG. 16**

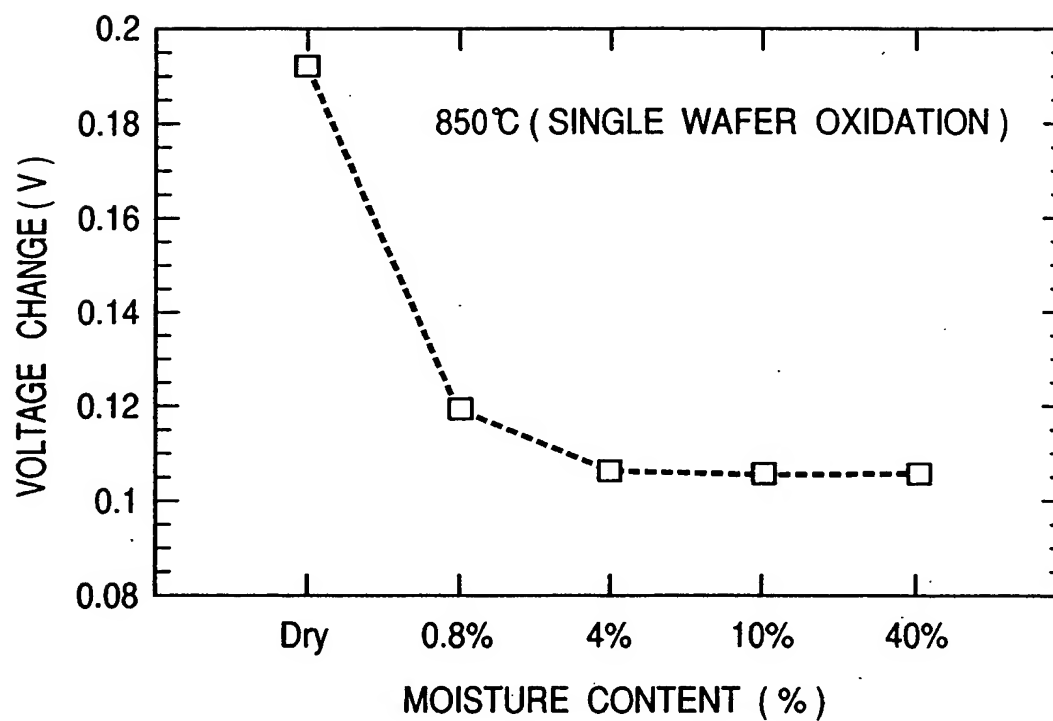


**FIG. 17**



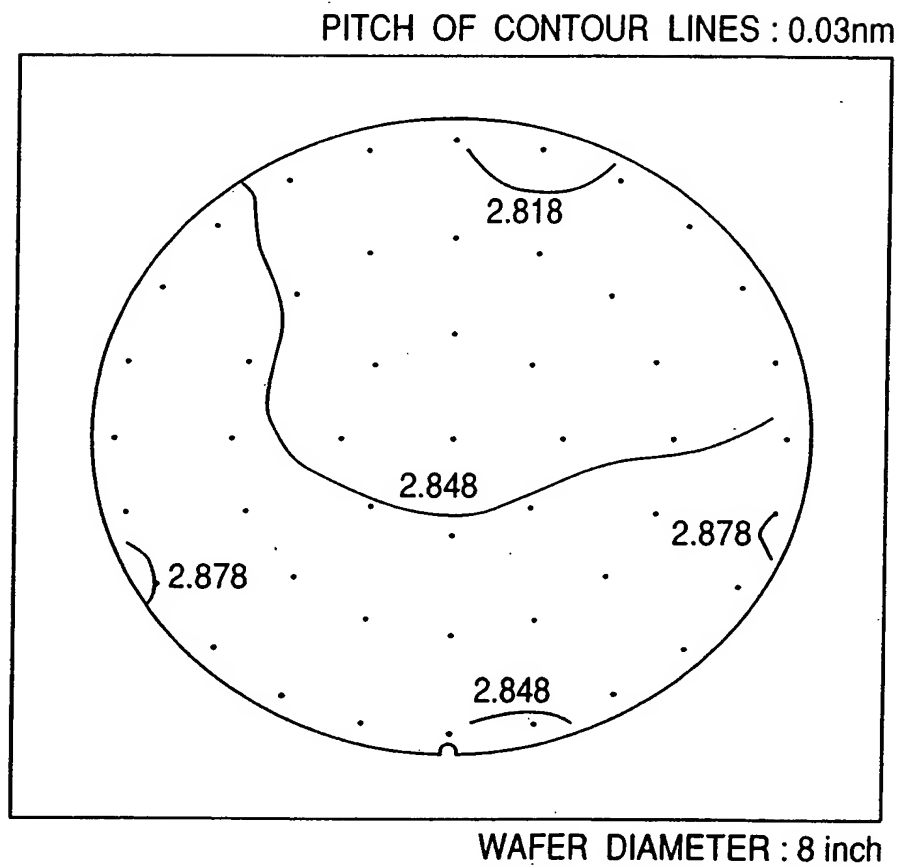
**FIG. 18**

INITIAL WITHSTAND VOLTAGE OF LOW MOISTURE  
CONTENT OXIDE FILM  
( OXIDE FILM THICKNESS = 9nm, S = 0.19 $\text{cm}^2$  )

**FIG. 19**

OXIDATION CONDITION DEPENDENCY  
OF VOLTAGE CHANGE

**FIG. 20**



AVERAGE : 2.848 [ nm ]

MAX. : 2.881 [ nm ]

MIN. : 2.814 [ nm ]

MAX. - MIN. : 0.067 [ nm ]

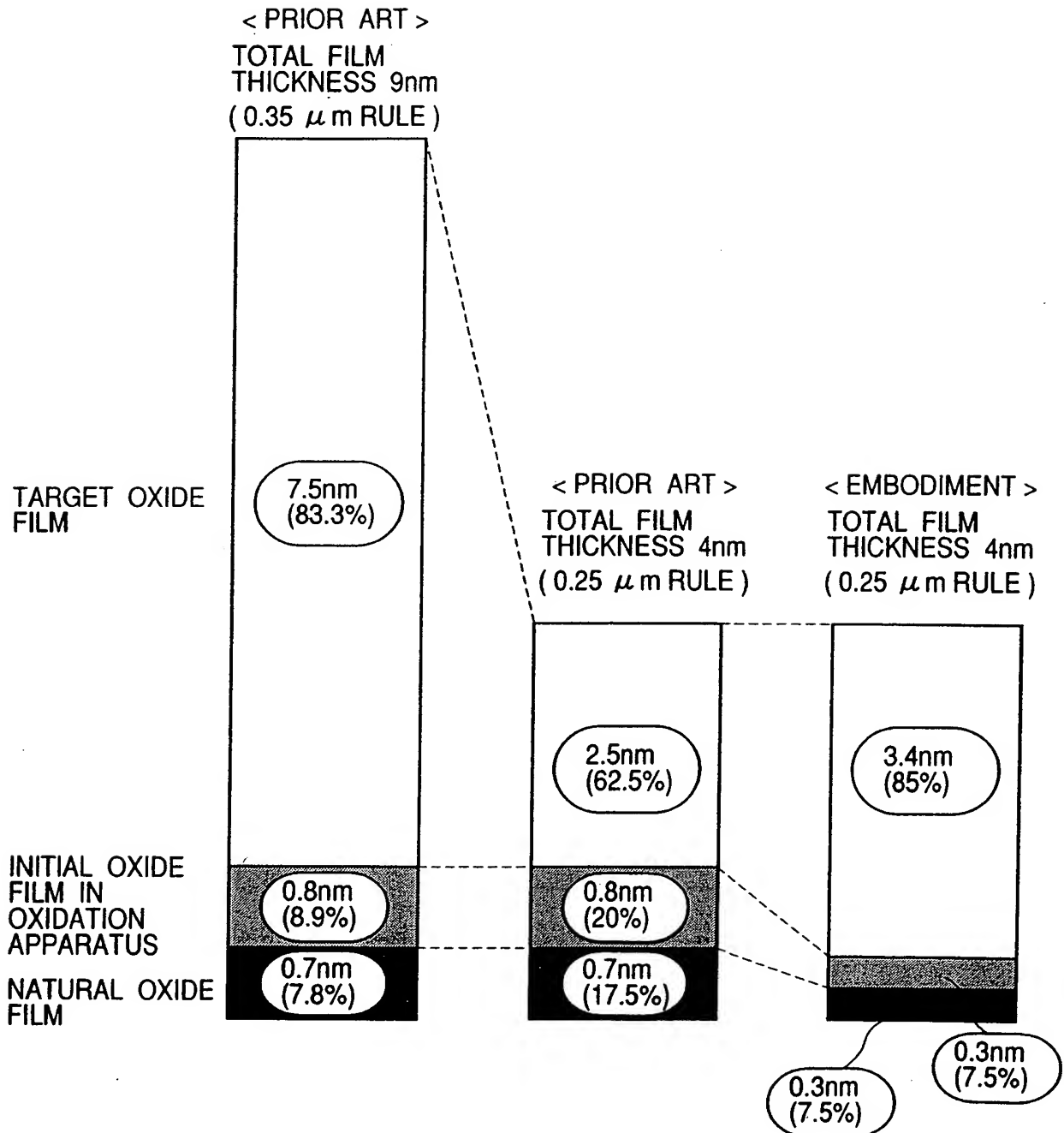
$\pm 1.18$  [ % ]

TREATING CONDITIONS : 850°C, 2'30"

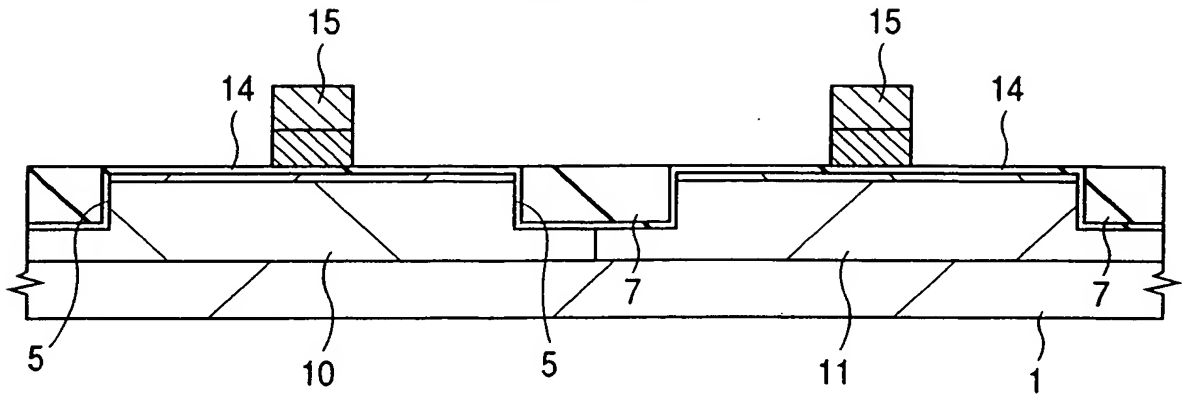
H<sub>2</sub> / O<sub>2</sub> : 0.05 / 4.9slm ( MOISTURE CONTENT : 0.8% )

MEASUREMENT : AT 49 POINTS BY ELLIPSOMETER

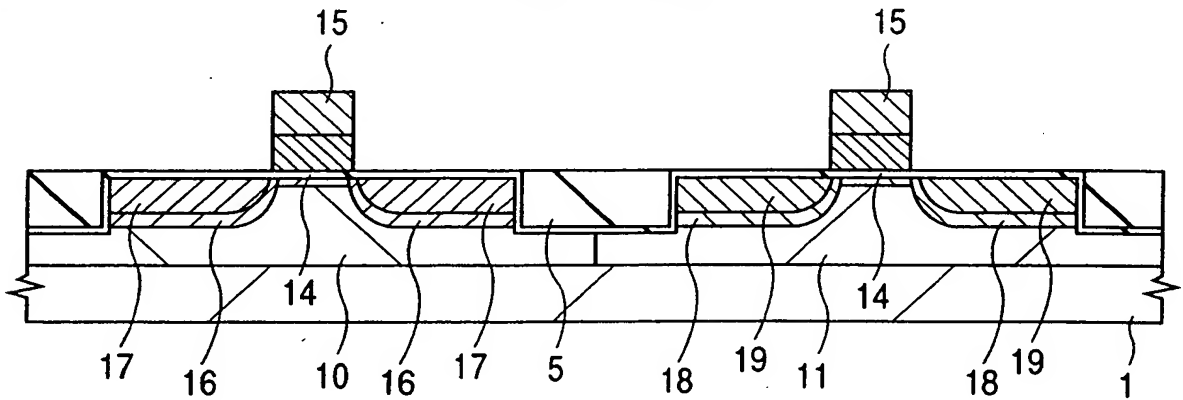
FIG. 21



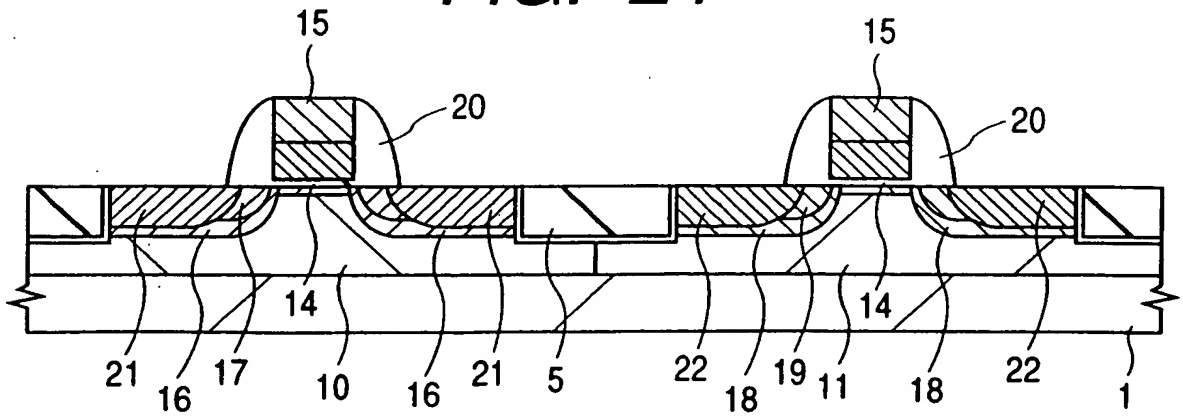
**FIG. 22**



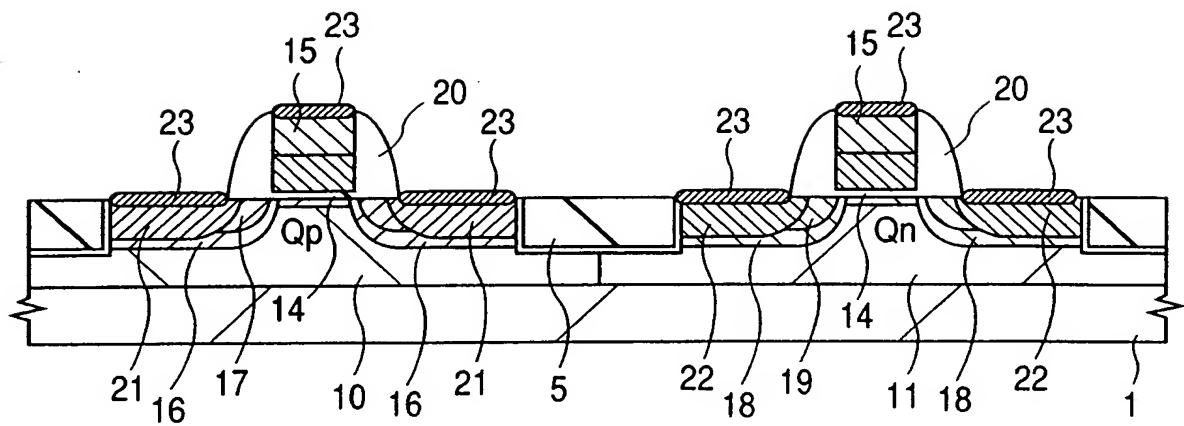
**FIG. 23**



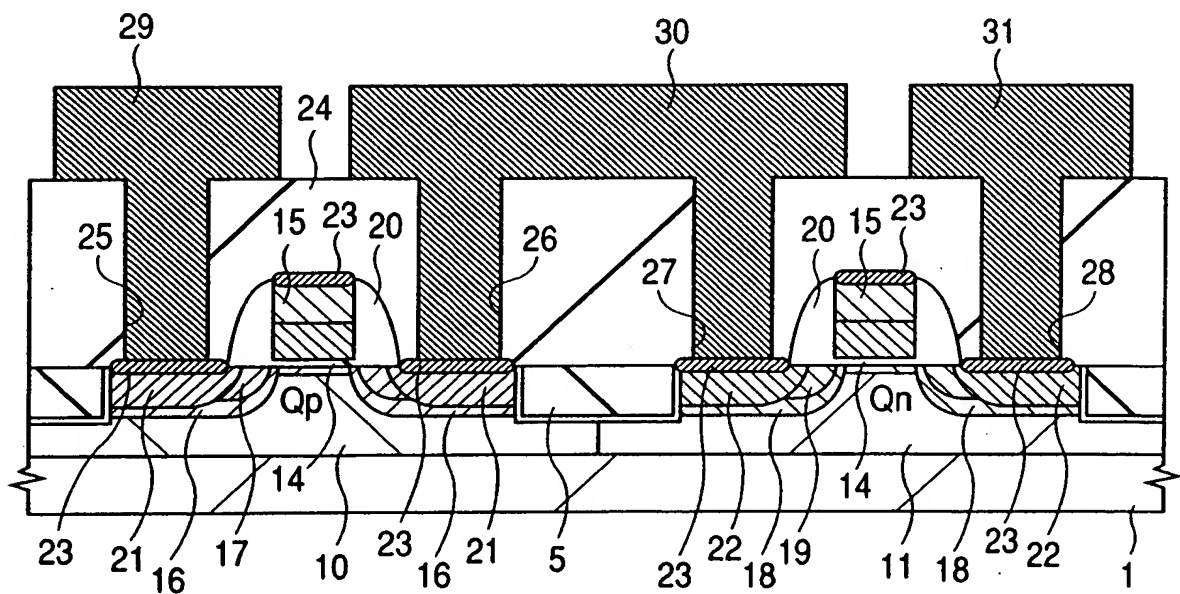
**FIG. 24**



**FIG. 25**

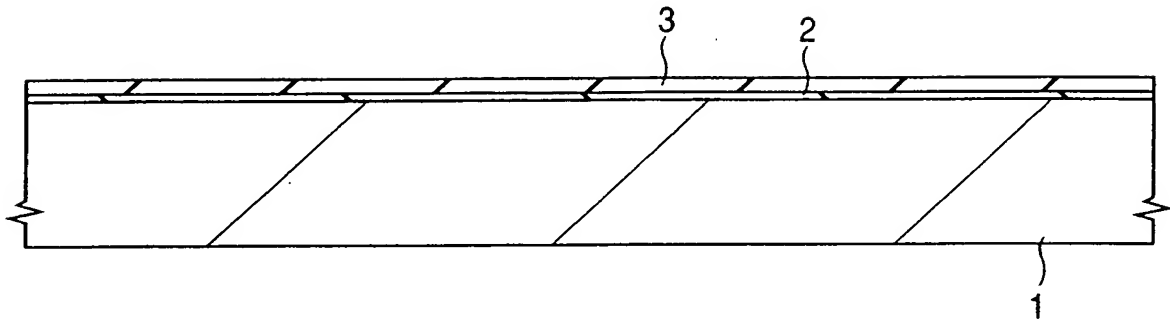


**FIG. 26**

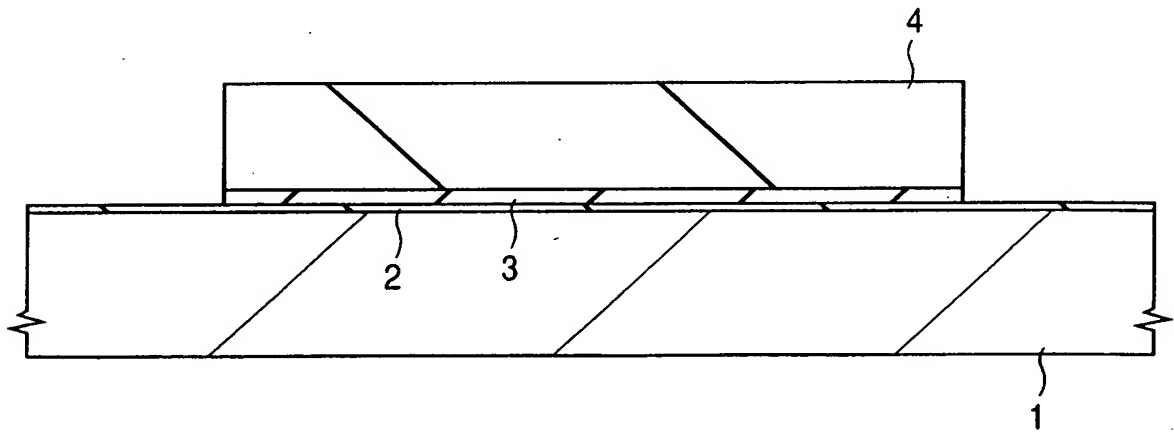




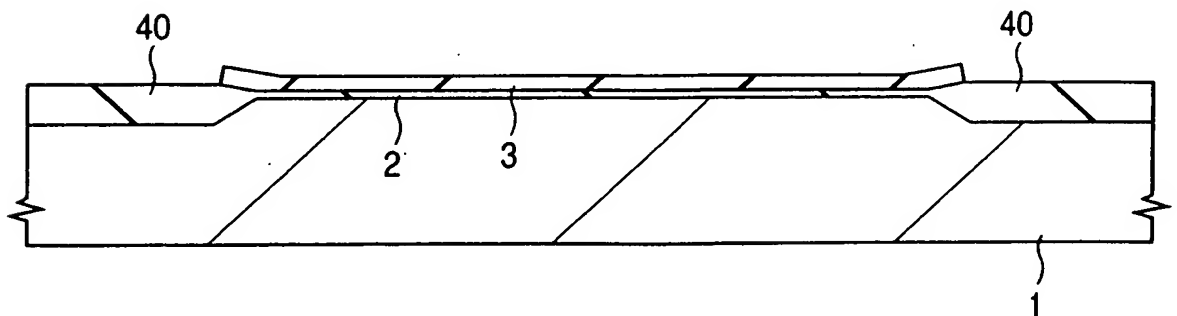
**FIG. 27**



**FIG. 28**



**FIG. 29**



*FIG. 30*

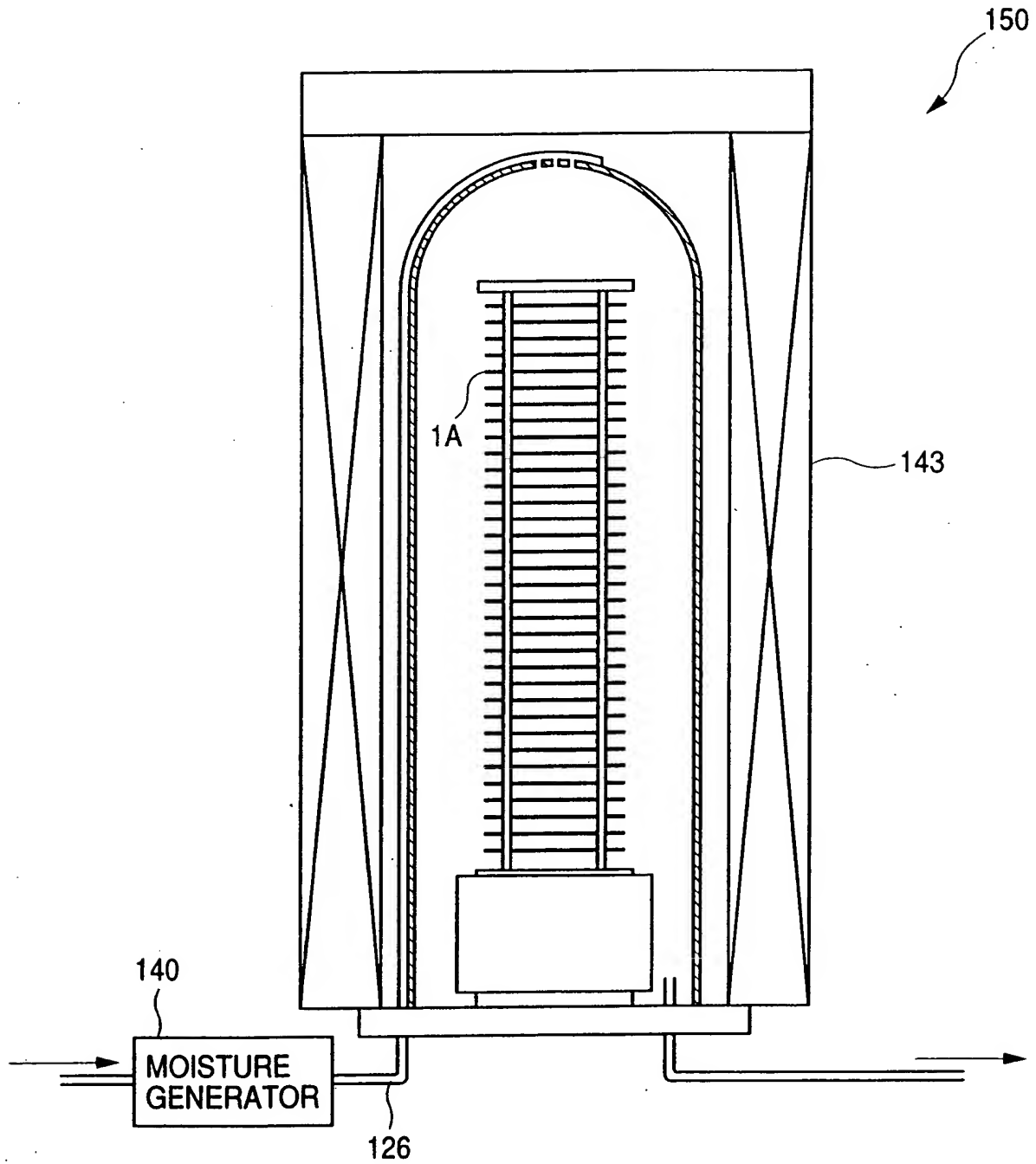
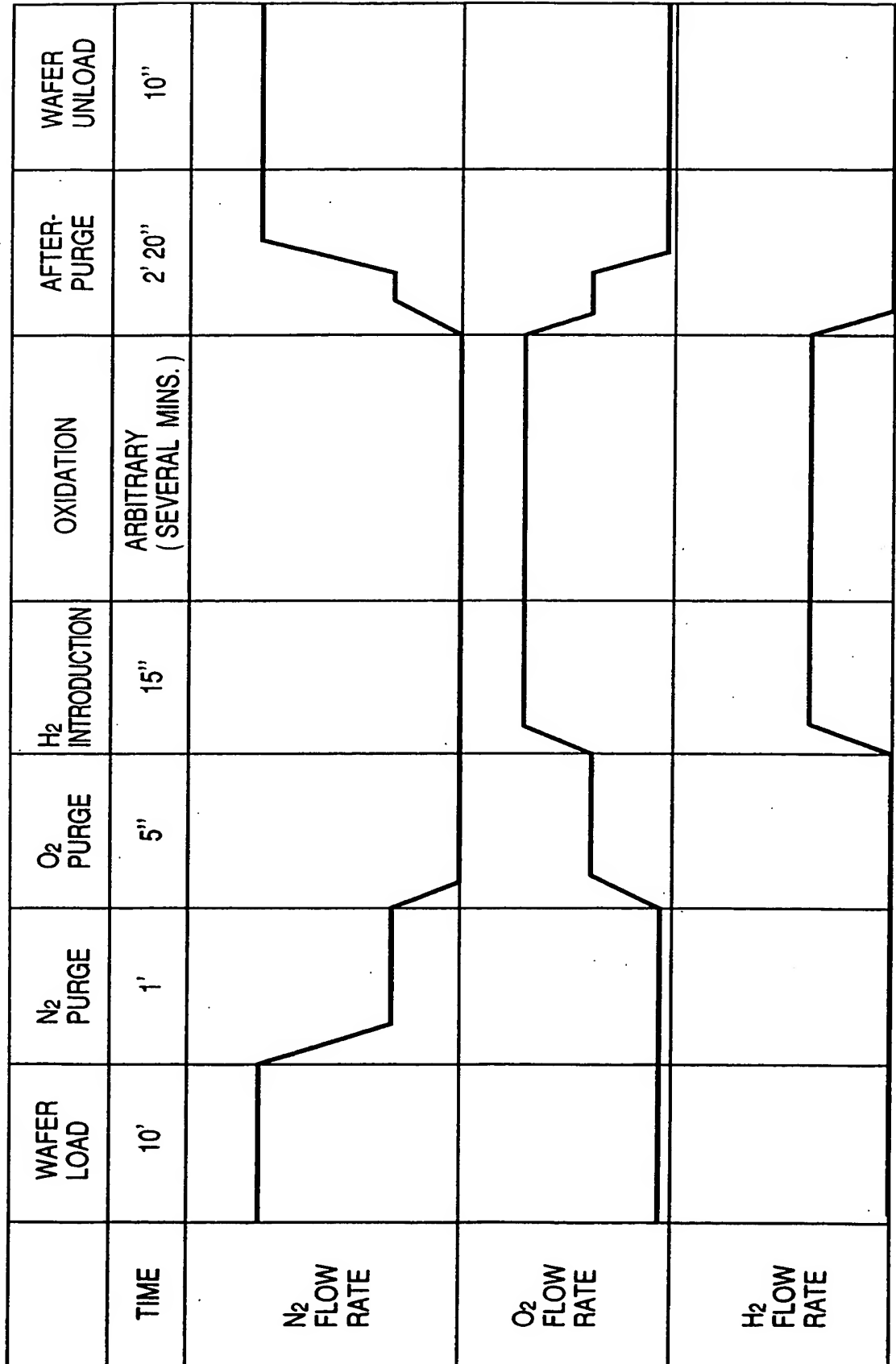
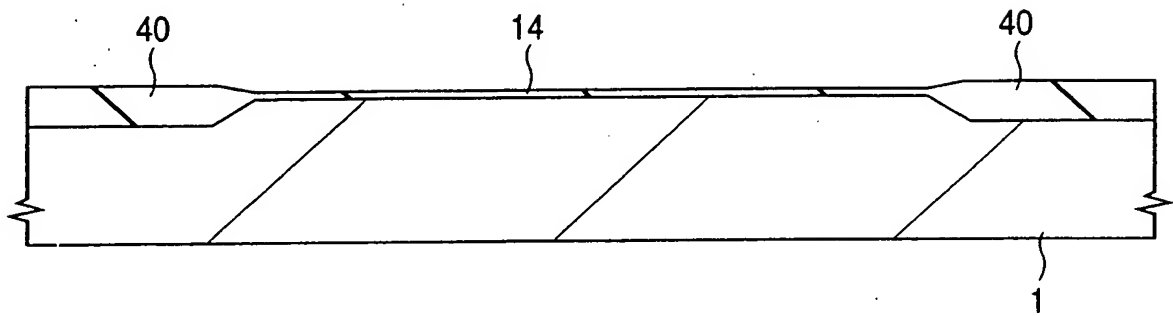


FIG. 31



**FIG. 32**



**FIG. 34**

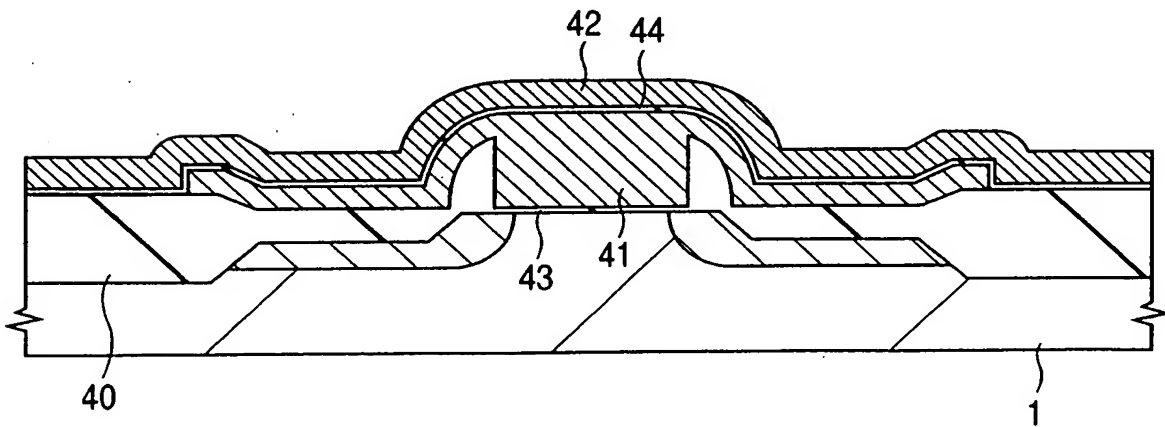


FIG. 33

